

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/966,419	VANDENAMEELE-LEPLA, PATRICK	
Examiner	Art Unit	_
Hona Cho	2662	

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	206-208, 482	10/28/2005	нс
375	152, 260	10/28/2005	НС
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
370	206, 482	10/28/2005	нс		
375	152, 260	10/28/2005	нс		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
370/206, 210, 281, 295, 343-344, 430, 480; 375/152, 220-222, 260 (text search - see search history printout)	8/29/2005 ·	нс		
370/210, 281, 295, 343-344, 430, 480; 375/152, 260	10/28/2005	нс		
consulted Tesfaldet Bocure for search in 375/222, 260; 370/208, 708/400- 405	11/9/2005	нс		